Se	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	er
10/750,580	HIGASHI ET AL.	
Examiner	Art Unit	
Thinh T Nauven	2818	

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257	777	12/5/2005	TTN
257	437	12/5/2005	TTN
257	433	12/6/2005	TTN
257	739	12/6/2005	TTN
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